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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	2560
Number of I/O	176
Number of Gates	54000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx36-fpq208



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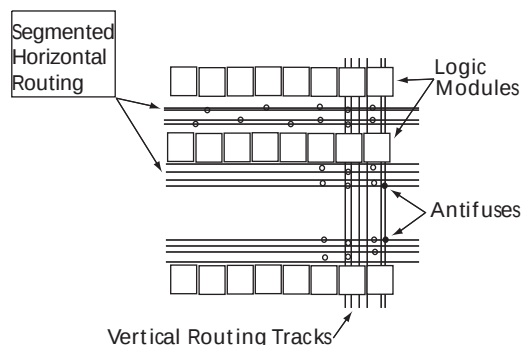
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3.2.3.3 Antifuse Structures

An antifuse is a “normally open” structure. The use of antifuses to implement a programmable logic device results in highly testable structures as well as efficient programming algorithms. There are no pre-existing connections; temporary connections can be made using pass transistors. These temporary connections can isolate individual antifuses to be programmed and individual circuit structures to be tested, which can be done before and after programming. For instance, all metal tracks can be tested for continuity and shorts between adjacent tracks, and the functionality of all logic modules can be verified.

Figure 7 • MX Routing Structure



3.2.4 Clock Networks

The 40MX devices have one global clock distribution network (CLK). A signal can be put on the CLK network by being routed through the CLKBUF buffer.

In 42MX devices, there are two low-skew, high-fanout clock distribution networks, referred to as CLKA and CLKB. Each network has a clock module (CLKMOD) that can select the source of the clock signal from any of the following (Figure 8, page 11):

- Externally from the CLKA pad, using CLKBUF buffer
- Externally from the CLKB pad, using CLKBUF buffer
- Internally from the CLKINTA input, using CLKINT buffer
- Internally from the CLKINTB input, using CLKINT buffer

The clock modules are located in the top row of I/O modules. Clock drivers and a dedicated horizontal clock track are located in each horizontal routing channel.

Clock input pads in both 40MX and 42MX devices can also be used as normal I/Os, bypassing the clock networks.

The A42MX36 device has four additional register control resources, called quadrant clock networks (Figure 9, page 11). Each quadrant clock provides a local, high-fanout resource to the contiguous logic modules within its quadrant of the device. Quadrant clock signals can originate from specific I/O pins or from the internal array and can be used as a secondary register clock, register clear, or output enable.

f_{q2} = Average second routed array clock rate in MHz)

Table 7 • Fixed Capacitance Values for MX FPGAs (pF)

Device Type	r1 routed_Clk1	r2 routed_Clk2
A40MX02	41.4	N/A
A40MX04	68.6	N/A
A42MX09	118	118
A42MX16	165	165
A42MX24	185	185
A42MX36	220	220

3.4.6 Test Circuitry and Silicon Explorer II Probe

MX devices contain probing circuitry that provides built-in access to every node in a design, via the use of Silicon Explorer II. Silicon Explorer II is an integrated hardware and software solution that, in conjunction with the Designer software, allow users to examine any of the internal nets of the device while it is operating in a prototyping or a production system. The user can probe into an MX device without changing the placement and routing of the design and without using any additional resources. Silicon Explorer II's noninvasive method does not alter timing or loading effects, thus shortening the debug cycle and providing a true representation of the device under actual functional situations.

Silicon Explorer II samples data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

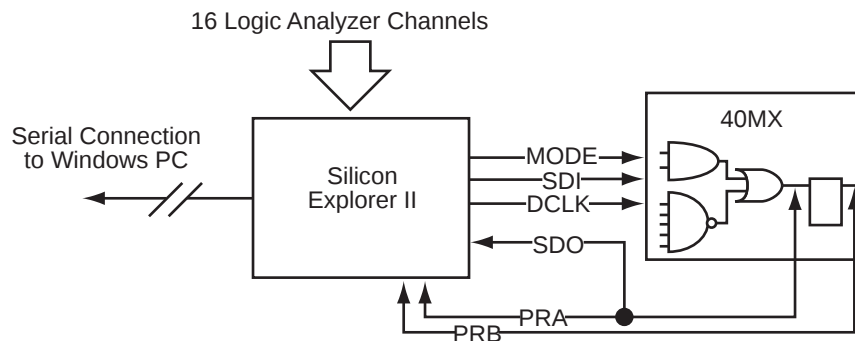
Silicon Explorer II is used to control the MODE, DCLK, SDI and SDO pins in MX devices to select the desired nets for debugging. The user simply assigns the selected internal nets in the Silicon Explorer II software to the PRA/PRB output pins for observation. Probing functionality is activated when the MODE pin is held HIGH.

Figure 12, page 16 illustrates the interconnection between Silicon Explorer II and 40MX devices, while Figure 13, page 17 illustrates the interconnection between Silicon Explorer II and 42MX devices

To allow for probing capabilities, the security fuses must not be programmed. (See [User Security](#), page 12 for the security fuses of 40MX and 42MX devices). Table 8, page 17 summarizes the possible device configurations for probing.

PRA and PRB pins are dual-purpose pins. When the "Reserve Probe Pin" is checked in the Designer software, PRA and PRB pins are reserved as dedicated outputs for probing. If PRA and PRB pins are required as user I/Os to achieve successful layout and "Reserve Probe Pin" is checked, the layout tool will override the option and place user I/Os on PRA and PRB pins.

Figure 12 • Silicon Explorer II Setup with 40MX

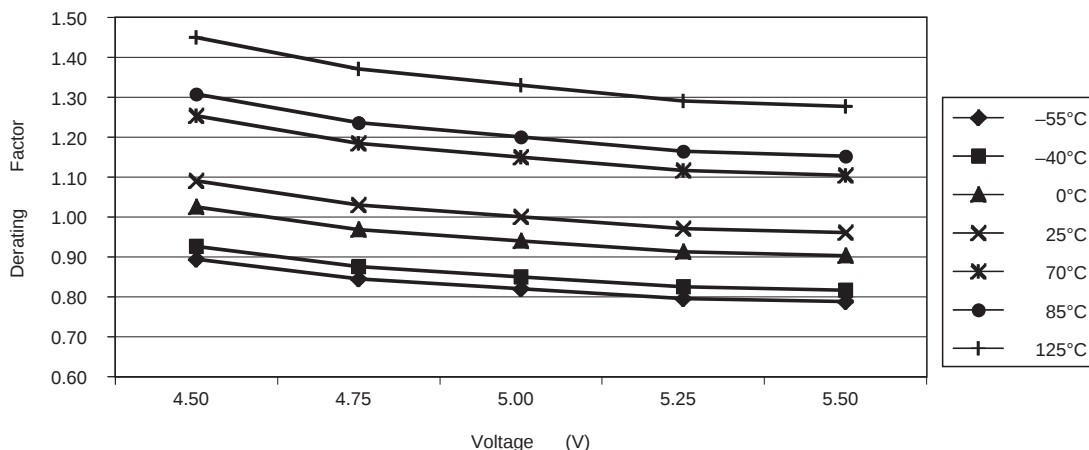


reliability. Devices should not be operated outside the recommended operating conditions.

Table 21 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	–40 to +85	–55 to +125	°C
VCCA	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
VCCI	3.14 to 3.47	3.0 to 3.6	3.0 to 3.6	V

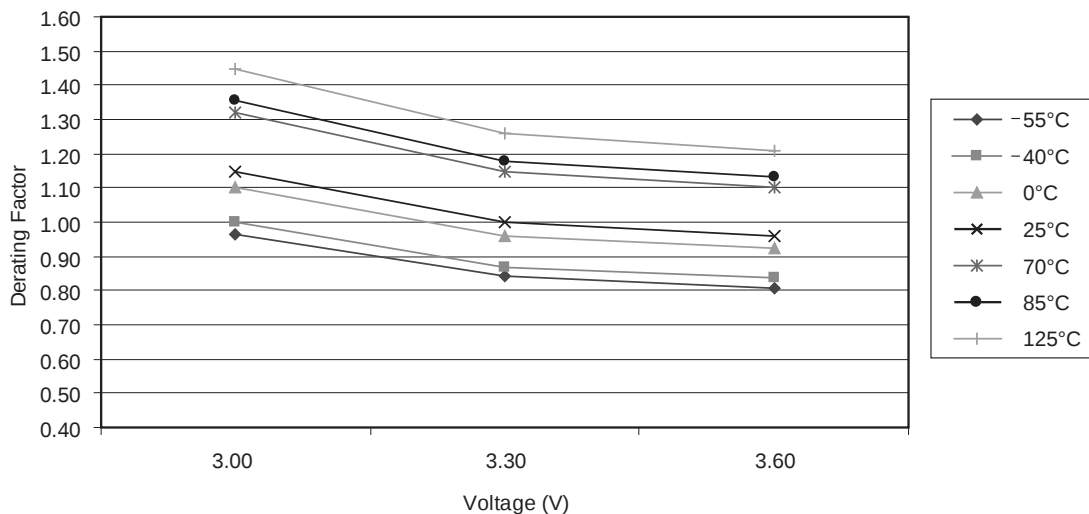
Note: *Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.

Figure 35 • 40MX Junction Temperature and Voltage Derating Curves (Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 5.0\text{ V}$)

Note: This derating factor applies to all routing and propagation delays

Table 30 • 42MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 3.3\text{ V}$)

42MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
3.00	0.97	1.00	1.10	1.15	1.32	1.36	1.45
3.30	0.84	0.87	0.96	1.00	1.15	1.18	1.26
3.60	0.81	0.84	0.92	0.96	1.10	1.13	1.21

Figure 36 • 42MX Junction Temperature and Voltage Derating Curves (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 3.3\text{ V}$)

Note: This derating factor applies to all routing and propagation delays

Table 31 • 40MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 3.3\text{ V}$)

40MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
3.00	1.08	1.12	1.21	1.26	1.50	1.64	2.00
3.30	0.86	0.89	0.96	1.00	1.19	1.30	1.59

Table 34 • A40MX02 Timing Characteristics (Nominal 5.0 V Operation) (continued)
 (Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Propagation Delays													
t _{INYH}	Pad-to-Y HIGH		0.7		0.8		0.9		1.1		1.5		ns
t _{INYL}	Pad-to-Y LOW		0.6		0.7		0.8		1.0		1.3		ns
Input Module Predicted Routing Delays ¹													
t _{IRD1}	FO = 1 Routing Delay		2.1		2.4		2.2		3.2		4.5		ns
t _{IRD2}	FO = 2 Routing Delay		2.6		3.0		3.4		4.0		5.6		ns
t _{IRD3}	FO = 3 Routing Delay		3.1		3.6		4.1		4.8		6.7		ns
t _{IRD4}	FO = 4 Routing Delay		3.6		4.2		4.8		5.6		7.8		ns
t _{IRD8}	FO = 8 Routing Delay		5.7		6.6		7.5		8.8		12.4		ns
Global Clock Network													
t _{CKH}	Input Low to HIGH	FO = 16 FO = 128	4.6 4.6		5.3 5.3		6.0 6.0		7.0 7.0		9.8 9.8		ns
t _{CKL}	Input High to LOW	FO = 16 FO = 128	4.8 4.8		5.6 5.6		6.3 6.3		7.4 7.4		10.4 10.4		ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 16 FO = 128	2.2 2.4	2.6 2.7		2.9 3.1		3.4 3.6		4.8 5.1		ns	
t _{PWL}	Minimum Pulse Width LOW	FO = 16 FO = 128	2.2 2.4	2.6 2.7		2.9 3.01		3.4 3.6		4.8 5.1		ns	
t _{CKSW}	Maximum Skew	FO = 16 FO = 128	0.4 0.5		0.5 0.6		0.5 0.7		0.6 0.8		0.8 1.2		ns
t _P	Minimum Period	FO = 16 FO = 128	4.7 4.8	5.4 5.6		6.1 6.3		7.2 7.5		10.0 10.4		ns	
f _{MAX}	Maximum Frequency	FO = 16 FO = 128	188 181		175 168		160 154		139 134		83 80		MHz

Table 36 • A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{HENA}	Flip-Flop (Latch) Enable Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		3.3		3.8		4.3		5.0		7.0		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		3.3		3.8		4.3		5.0		7.0		ns
t _A	Flip-Flop Clock Input Period		4.8		5.6		6.3		7.5		10.4		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)			181		167		154		134		80	MHz
Input Module Propagation Delays													
t _{INYH}	Pad-to-Y HIGH			0.7		0.8		0.9		1.1		1.5	ns
t _{INYL}	Pad-to-Y LOW			0.6		0.7		0.8		1.0		1.3	ns
Input Module Predicted Routing Delays ¹													
t _{IRD1}	FO = 1 Routing Delay			2.1		2.4		2.2		3.2		4.5	ns
t _{IRD2}	FO = 2 Routing Delay			2.6		3.0		3.4		4.0		5.6	ns
t _{IRD3}	FO = 3 Routing Delay			3.1		3.6		4.1		4.8		6.7	ns
t _{IRD4}	FO = 4 Routing Delay			3.6		4.2		4.8		5.6		7.8	ns
t _{IRD8}	FO = 8 Routing Delay			5.7		6.6		7.5		8.8		12.4	ns
Global Clock Network													
t _{CKH}	Input Low to HIGH	FO = 16		4.6		5.3		6.0		7.0		9.8	ns
		FO = 128		4.6		5.3		6.0		7.0		9.8	
t _{CKL}	Input High to LOW	FO = 16		4.8		5.6		6.3		7.4		10.4	ns
		FO = 128		4.8		5.6		6.3		7.4		10.4	
t _{PWH}	Minimum Pulse Width HIGH	FO = 16	2.2		2.6		2.9		3.4		4.8		ns
		FO = 128	2.4		2.7		3.1		3.6		5.1		
t _{PWL}	Minimum Pulse Width LOW	FO = 16	2.2		2.6		2.9		3.4		4.8		ns
		FO = 128	2.4		2.7		3.01		3.6		5.1		
t _{CKSW}	Maximum Skew	FO = 16		0.4		0.5		0.5		0.6		0.8	ns
		FO = 128		0.5		0.6		0.7		0.8		1.2	
t _P	Minimum Period	FO = 16	4.7		5.4		6.1		7.2		10.0		ns
		FO = 128	4.8		5.6		6.3		7.5		10.4		
f _{MAX}	Maximum Frequency	FO = 16		188		175		160		139		83	MHz
		FO = 128		181		168		154		134		80	
TTL Output Module Timing ⁴													
t _{DLH}	Data-to-Pad HIGH			3.3		3.8		4.3		5.1		7.2	ns
t _{DHL}	Data-to-Pad LOW			4.0		4.6		5.2		6.1		8.6	ns
t _{ENZH}	Enable Pad Z to HIGH			3.7		4.3		4.9		5.8		8.0	ns
t _{ENZL}	Enable Pad Z to LOW			4.7		5.4		6.1		7.2		10.1	ns
t _{ENHZ}	Enable Pad HIGH to Z			7.9		9.1		10.4		12.2		17.1	ns

Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁴												
t _{DLH}	Data-to-Pad HIGH		5.5		6.4		7.2		8.5		11.9	ns
t _{DHL}	Data-to-Pad LOW		4.8		5.5		6.2		7.3		10.2	ns
t _{ENZH}	Enable Pad Z to HIGH		4.7		5.5		6.2		7.3		10.2	ns
t _{ENZL}	Enable Pad Z to LOW		6.8		7.9		8.9		10.5		14.7	ns
t _{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1		23.9	ns
t _{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6		17.7	ns
d _{TLH}	Delta LOW to HIGH		0.05		0.05		0.06		0.07		0.10	ns/pF
d _{THL}	Delta HIGH to LOW		0.03		0.03		0.04		0.04		0.06	ns/pF

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro.
4. Delays based on 35 pF loading.

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays ¹												
t _{PD1}	Single Module		1.2		1.3		1.5		1.8		2.5	ns
t _{CO}	Sequential Clock-to-Q		1.3		1.4		1.6		1.9		2.7	ns
t _{GO}	Latch G-to-Q		1.2		1.4		1.6		1.8		2.6	ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.6		1.8		2.1		2.9	ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay		0.7		0.8		0.9		1.0		1.4	ns
t _{RD2}	FO = 2 Routing Delay		0.9		1.0		1.2		1.4		1.9	ns
t _{RD3}	FO = 3 Routing Delay		1.2		1.3		1.5		1.7		2.4	ns
t _{RD4}	FO = 4 Routing Delay		1.4		1.5		1.7		2.0		2.9	ns
t _{RD8}	FO = 8 Routing Delay		2.3		2.6		2.9		3.4		4.8	ns
Logic Module Sequential Timing ^{3, 4}												
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up	0.3		0.4		0.4		0.5		0.7		ns
t _{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.4		0.5		0.5		0.6		0.8		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.4		3.8		4.3		5.0		7.0		ns

Table 43 • A42MX24 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description			-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Predicted Routing Delays ²													
t _{IRD1}	FO = 1 Routing Delay		2.6		2.9		3.2		3.8		5.3		ns
t _{IRD2}	FO = 2 Routing Delay		2.9		3.2		3.6		4.3		6.0		ns
t _{IRD3}	FO = 3 Routing Delay		3.2		3.6		4.0		4.8		6.6		ns
t _{IRD4}	FO = 4 Routing Delay		3.5		3.9		4.4		5.2		7.3		ns
t _{IRD8}	FO = 8 Routing Delay		4.8		5.3		6.1		7.1		10.0		ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 32	4.4		4.8		5.5		6.5		9.1		ns
		FO = 486	4.8		5.3		6.0		7.1		10.0		ns
t _{CKL}	Input HIGH to LOW	FO = 32	5.1		5.7		6.4		7.6		10.6		ns
		FO = 486	6.0		6.6		7.5		8.8		12.4		ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	3.0	3.3		3.8		4.5		6.3		ns	
		FO = 486	3.3	3.7		4.2		4.9		6.9		ns	
t _{PWL}	Minimum Pulse Width LOW	FO = 32	3.0	3.4		3.8		4.5		6.3		ns	
		FO = 486	3.3	3.7		4.2		4.9		6.9		ns	
t _{CKSW}	Maximum Skew	FO = 32	0.8		0.8		1.0		1.1		1.6		ns
		FO = 486	0.8		0.8		1.0		1.1		1.6		ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0	0.0		0.0		0.0		0.0		ns	
		FO = 486	0.0	0.0		0.0		0.0		0.0		ns	
TTL Output Module Timing ⁵													
t _{DLH}	Data-to-Pad HIGH		3.4		3.8		4.3		5.0		7.1		ns
t _{DHL}	Data-to-Pad LOW		4.0		4.4		5.0		5.9		8.3		ns
t _{ENZH}	Enable Pad Z to HIGH		3.6		4.0		4.5		5.3		7.4		ns
t _{ENZL}	Enable Pad Z to LOW		3.9		4.4		5.0		5.8		8.2		ns
t _{ENHZ}	Enable Pad HIGH to Z		7.2		8.0		9.1		10.7		14.9		ns
t _{ENLZ}	Enable Pad LOW to Z		6.7		7.5		8.5		9.9		13.9		ns
t _{GLH}	G-to-Pad HIGH		4.8		5.3		6.0		7.2		10.0		ns
t _{GHL}	G-to-Pad LOW		4.8		5.3		6.0		7.2		10.0		ns
t _{LSU}	I/O Latch Output Set-Up		0.7		0.7		0.8		1.0		1.4		ns

Clock signal to shift the Boundary Scan Test (BST) data into the device. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDI, I/O Test Data In

Serial data input for BST instructions and data. Data is shifted in on the rising edge of TCK. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDO, I/O Test Data Out

Serial data output for BST instructions and test data. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TMS, I/O Test Mode Select

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI and TDO pins are boundary scan pins. Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications. IEEE JTAG specification recommends a 10k Ω pull-up resistor on the pin. BST pins are only available in A42MX24 and A42MX36 devices.

VCC, Supply Voltage

Input supply voltage for 40MX devices

VCCA, Supply Voltage

Supply voltage for array in 42MX devices

VCCI, Supply Voltage

Supply voltage for I/Os in 42MX devices

WD, I/O Wide Decode Output

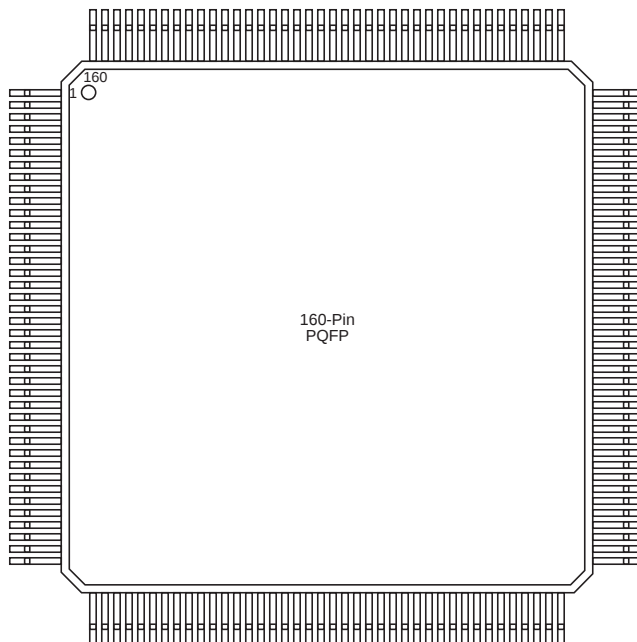
When a wide decode module is used in a 42MX device this pin can be used as a dedicated output from the wide decode module. This direct connection eliminates additional interconnect delays associated with regular logic modules. To implement the direct I/O connection, connect an output buffer of any type to the output of the wide decode macro and place this output on one of the reserved WD pins.

Table 50 • PQ 100

PQ100				
Pin Number	A40MX02 Function	A40MX04 Function	A42MX09 Function	A42MX16 Function
19	VCC	V _{CC}	I/O	I/O
20	I/O	I/O	I/O	I/O
21	I/O	I/O	I/O	I/O
22	I/O	I/O	GND	GND
23	I/O	I/O	I/O	I/O
24	I/O	I/O	I/O	I/O
25	I/O	I/O	I/O	I/O
26	I/O	I/O	I/O	I/O
27	NC	NC	I/O	I/O
28	NC	NC	I/O	I/O
29	NC	NC	I/O	I/O
30	NC	NC	I/O	I/O
31	NC	I/O	I/O	I/O
32	NC	I/O	I/O	I/O
33	NC	I/O	I/O	I/O
34	I/O	I/O	GND	GND
35	I/O	I/O	I/O	I/O
36	GND	GND	I/O	I/O
37	GND	GND	I/O	I/O
38	I/O	I/O	I/O	I/O
39	I/O	I/O	I/O	I/O
40	I/O	I/O	VCCA	VCCA
41	I/O	I/O	I/O	I/O
42	I/O	I/O	I/O	I/O
43	VCC	VCC	I/O	I/O
44	VCC	VCC	I/O	I/O
45	I/O	I/O	I/O	I/O
46	I/O	I/O	GND	GND
47	I/O	I/O	I/O	I/O
48	NC	I/O	I/O	I/O
49	NC	I/O	I/O	I/O
50	NC	I/O	I/O	I/O
51	NC	NC	I/O	I/O
52	NC	NC	SDO, I/O	SDO, I/O
53	NC	NC	I/O	I/O
54	NC	NC	I/O	I/O
55	NC	NC	I/O	I/O

Table 50 • PQ 100

PQ100				
Pin Number	A40MX02 Function	A40MX04 Function	A42MX09 Function	A42MX16 Function
93	VCC	VCC	I/O	I/O
94	VCC	VCC	PRB, I/O	PRB, I/O
95	NC	I/O	I/O	I/O
96	NC	I/O	GND	GND
97	NC	I/O	I/O	I/O
98	SDI, I/O	SDI, I/O	I/O	I/O
99	DCLK, I/O	DCLK, I/O	I/O	I/O
100	PRA, I/O	PRA, I/O	I/O	I/O

Figure 43 • PQ160**Table 52 • PQ160**

PQ160			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
1	I/O	I/O	I/O
2	DCLK, I/O	DCLK, I/O	DCLK, I/O
3	NC	I/O	I/O
4	I/O	I/O	WD, I/O
5	I/O	I/O	WD, I/O
6	NC	VCCI	VCCI
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	I/O	I/O	I/O
10	NC	I/O	I/O
11	GND	GND	GND
12	NC	I/O	I/O
13	I/O	I/O	WD, I/O
14	I/O	I/O	WD, I/O
15	I/O	I/O	I/O
16	PRB, I/O	PRB, I/O	PRB, I/O
17	I/O	I/O	I/O
18	CLKB, I/O	CLKB, I/O	CLKB, I/O
19	I/O	I/O	I/O
20	VCCA	VCCA	VCCA

Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
21	I/O	I/O	I/O
22	GND	GND	GND
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	GND	GND	GND
28	VCCI	VCCI	VCCI
29	VCCA	VCCA	VCCA
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	VCCA	VCCA	VCCA
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	I/O	I/O	I/O
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	NC	I/O	I/O
42	NC	I/O	I/O
43	NC	I/O	I/O
44	I/O	I/O	I/O
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	NC	I/O	I/O
51	NC	I/O	I/O
52	GND	GND	GND
53	GND	GND	GND
54	I/O	TMS, I/O	TMS, I/O
55	I/O	TDI, I/O	TDI, I/O
56	I/O	I/O	I/O
57	I/O	WD, I/O	WD, I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
200	I/O
201	I/O
202	I/O
203	I/O
204	I/O
205	I/O
206	VCCA
207	I/O
208	I/O
209	VCCA
210	VCCI
211	I/O
212	I/O
213	I/O
214	I/O
215	I/O
216	I/O
217	I/O
218	I/O
219	VCCA
220	I/O
221	I/O
222	I/O
223	I/O
224	I/O
225	I/O
226	I/O
227	VCCI
228	I/O
229	I/O
230	I/O
231	I/O
232	I/O
233	I/O
234	I/O
235	I/O
236	I/O

Table 55 • VQ80

VQ80		
Pin Number	A40MX02 Function	A40MX04 Function
49	I/O	I/O
50	CLK, I/O	CLK, I/O
51	I/O	I/O
52	MODE	MODE
53	VCC	VCC
54	NC	I/O
55	NC	I/O
56	NC	I/O
57	SDI, I/O	SDI, I/O
58	DCLK, I/O	DCLK, I/O
59	PRA, I/O	PRA, I/O
60	NC	NC
61	PRB, I/O	PRB, I/O
62	I/O	I/O
63	I/O	I/O
64	I/O	I/O
65	I/O	I/O
66	I/O	I/O
67	I/O	I/O
68	GND	GND
69	I/O	I/O
70	I/O	I/O
71	I/O	I/O
72	I/O	I/O
73	I/O	I/O
74	VCC	VCC
75	I/O	I/O
76	I/O	I/O
77	I/O	I/O
78	I/O	I/O
79	I/O	I/O
80	I/O	I/O

Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
47	I/O	I/O	TDI, I/O
48	I/O	I/O	I/O
49	I/O	I/O	WD, I/O
50	I/O	I/O	WD, I/O
51	I/O	I/O	I/O
52	NC	VCCI	VCCI
53	I/O	I/O	I/O
54	NC	I/O	I/O
55	NC	I/O	WD, I/O
56	I/O	I/O	WD, I/O
57	NC	NC	I/O
58	I/O	I/O	I/O
59	I/O	I/O	WD, I/O
60	I/O	I/O	WD, I/O
61	NC	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	NC	I/O	I/O
65	I/O	I/O	I/O
66	NC	I/O	I/O
67	GND	GND	GND
68	VCCA	VCCA	VCCA
69	I/O	I/O	WD, I/O
70	I/O	I/O	WD, I/O
71	I/O	I/O	I/O
72	I/O	I/O	I/O
73	I/O	I/O	I/O
74	NC	I/O	I/O
75	I/O	I/O	I/O
76	I/O	I/O	I/O
77	NC	NC	WD, I/O
78	NC	I/O	WD, I/O
79	I/O	I/O	I/O
80	NC	I/O	I/O
81	I/O	I/O	I/O
82	NC	VCCI	VCCI
83	I/O	I/O	I/O

Table 58 • CQ208

CQ208	
Pin Number	A42MX36 Function
74	I/O
75	I/O
76	I/O
77	I/O
78	GND
79	VCCA
80	VCCI
81	I/O
82	I/O
83	I/O
84	I/O
85	WD, I/O
86	WD, I/O
87	I/O
88	I/O
89	I/O
90	I/O
91	QCLKB, I/O
92	I/O
93	WD, I/O
94	WD, I/O
95	I/O
96	I/O
97	I/O
98	VCCI
99	I/O
100	WD, I/O
101	WD, I/O
102	I/O
103	TDO, I/O
104	I/O
105	GND
106	VCCA
107	I/O
108	I/O
109	I/O
110	I/O

Table 60 • BG272

BG272	
Pin Number	A42MX36 Function
D20	I/O
E1	I/O
E2	I/O
E3	I/O
E4	VCCA
E17	VCCI
E18	I/O
E19	I/O
E20	I/O
F1	I/O
F2	I/O
F3	I/O
F4	VCCI
F17	I/O
F18	I/O
F19	I/O
F20	I/O
G1	I/O
G2	I/O
G3	I/O
G4	VCCI
G17	VCCI
G18	I/O
G19	I/O
G20	I/O
H1	I/O
H2	I/O
H3	I/O
H4	VCCA
H17	I/O
H18	I/O
H19	I/O
H20	I/O
J1	I/O
J2	I/O
J3	I/O
J4	VCCI